

Form PTO-1449
(Rev. 8-83)U.S. Department of Commerce
Patent and Trademark OfficeAttorney Docket No.
0756-2218

Serial No. Not Yet Assigned

INFORMATION DISCLOSURE STATEMENT

(Use several sheets if necessary)

Applicant: Hongyong ZHANG et al

Filing Date: October 25, 2000

Group: 2813

U.S. PATENT DOCUMENTS

Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date (if appropriate)
EP	4,657,775	04/14/1987	Shiori et al	-	-	
EP	5,654,203	11/23/1994	Ohtani et al	-	-	
EP	5,808,321	06/07/1994	Mitanaga et al	-	-	
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EP	5,352,631	10/04/1994	Sitaram et al	-	-	
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EP	5,481,121	01/02/1996	Zhang et al	-	-	
EP	5,488,000	01/30/1998	Zhang et al	-	-	

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	Document Number	Date	Country	Class	Subclass	Translation	
						Yes	No
EP	EP 0 174 553 A2	03/19/1986	Europe				
EP	61-070716	04/11/1986	Japan			Abstract	
EP	6-029212	02/04/1994	Japan			Abstract	
EP	2-140915	05/30/1990	Japan	437	40TFT		
EP	63-155714	06/28/1988	Japan				
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EP	2-222546	09/05/1990	Japan				
EP	5-90518	04/09/1993	Japan				

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

EP	F. Spaepen et al., Crucial issues in Semic. Mat. & Proc. Technol., S. Coffa et al., eds, Metal-enhanced Growth of Si
EP	J.E. Greene et al., Thin Solid Films 34 (1976) 27, "Metal induced crystallization of R.F. sputtered a Si-films"
	ASM Handbook, Vol. 5, p510-531 (1994)

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Evan Pert

Date Considered

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Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date (if appropriate)
EP	5,147,826	09/15/1992	Liu et al	437	233	
EP	4,796,083	01/03/1989	Cherukuvi et al			
EP	5,275,851	01/04/1994	Fonash et al	437	233	03/03/1993
EP	5,264,383	11/23/1993	Young	437	40TFT	
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Document Number	Date	Country	Class	Subclass	Translation Yes No

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

EP	G. Radnoczi et al., J. Appl. Phys., 69(9) (1991) 6394, "Al induced crystallization of a Si"
EP	A.V. Dvurechenskii et al., "Transport Phenomena in Amorphous Silicon Doped by Ion Implanataion of 3 rd Metals", Akademikian Lavrentec Propsekt 13, 630090 Novosibrisk 90, USSR, pp. 635-640
EP	T. Hempel, et al. Solid State Comm., 85,11(1993)921 "Needle-Like Crystallization of Ni Doped A-Si Thin Films"
EP	J.R. Bosnell, et al., Thin Solid Films, 6(1970) 161 "...The Influence of Contact Materials or ... Crystallization..."
EP	C. Hayzelden et al., Appl. Phys. Lett., 60,2(1992)225 "...TEM Studies of Silicide Mediated Crystallization..."
EP	Y.N. Efokhin, et al., Appl. Phys. Lett., 63,23(1993) 3173 "... NiSiz Formation ... on Preamorphized Silicon ..."
EP	T.T. Ngo, et al., Appl. Phys. Left. 66,15(1995) 1906-1908 "... Growth of Monodisperse Islands"
EP	Y. Kawazu et al., Jpn. J. Appl. Phys., 29,12(1990)2698 "...Crystallization of A-Si:H Induced by Nickel..."
EP	D. Tonneau et al., J. de Physique, coll. C5, 5,50(1989)647 "...Metal Carbonyis for CVD of Microstrues"
EP	S. Wolfe & R.N. Tavber, "Silicon Processing got the VLSI Era" Vol I, 1986, P. 51-3, 335

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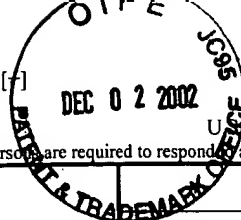
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Substitute for form 1449A/PTO INFORMATION DISCLOSURE STATEMENT BY APPLICANT <i>(use as many sheets as necessary)</i>				Complete if Known		
				Application Number		09/695,414
				Filing Date		October 25, 2000
				First Named Inventor		Hongyong ZHANG et al.
				Group Art Unit		2829
				Examiner Name		E. Pert
Sheet	1	of	1	Attorney Docket Number		0756-2218

U.S. PATENT DOCUMENTS						
Examiner Initials*	Cite No. ¹	U.S. Patent Document		Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number	Kind Code ² (if known)			
EP		5,861,337		Zhang et al.	01/19/1999	
EP		6,174,374	B1	Zhang et al.	01/16/2001	
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FOREIGN PATENT DOCUMENTS							
Examiner Initials*	Cite No. ¹	Foreign Patent Document			Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
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OTHER PRIOR ART - NON PATENT LITERATURE DOCUMENTS			
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